## Notice of References Cited Application/Control No. 10/551,817 Examiner Sharad Rampuria U.S. PATENT DOCUMENTS Applicant(s)/Patent Under Reexamination LIN ET AL. Art Unit 2617 Page 1 of 1

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,374,112 B1	04-2002	Widegren et al.	455/452.2
*	В	US-6,801,508 B1	10-2004	Lim, Byung Keun	370/310.1
	U	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	L_	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.